

PEIR 2000 HR Series

Seiwa PE IR 2000HR Series lens are color corrected from 1000nm-2000nm wavelength.

It's high resolution and high throughput design enables collection of weak signals from samples without re-focusing.

In addition, this lens is able to correct 0-700 micron thickness of silicon and glass.

Both 20X (NA:0.6) and 50X (NA:0.7) are available.



Specifications

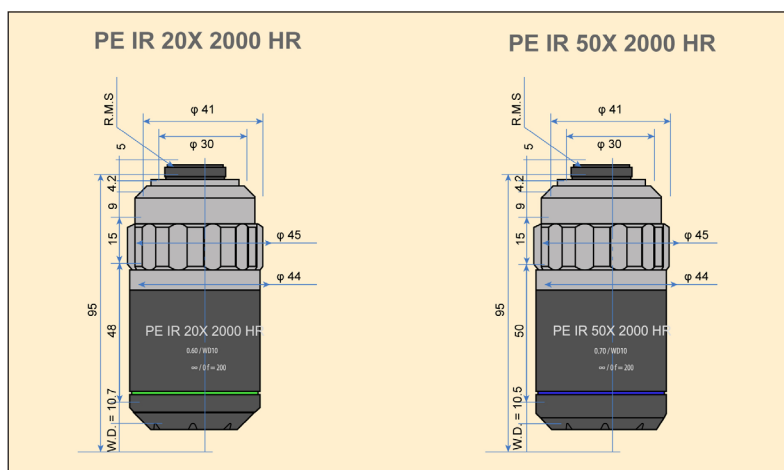
Model	PE IR 20X 2000 HR	PE IR 50X 2000 HR
Resolution *1	1.6 μm	1.4 μm
Working Distance *2	10	10
N.A	0.6	0.7-
Transmission Rate*3	1300nm > 80% 2000nm > 80%	300nm > 80% 2000nm > 80 %
Focal Shift *3	Less than $\pm 1.3\mu\text{m}$ (1300 - 2000 μm)	Less than $\pm 1.3\mu\text{m}$ (1300 -2000 μm)
Chromatic Aberration*3 Standard Wavelength 1550nm	1300 μm - 2.43 μm 2000 μm - 12.26 μm	1300 μm - 2.20 μm 2000 μm - 12.19 μm
Silicon Correcting *4	<700 μm	<700 μm
Parfocal Distance	95mm	95mm

*1 The resolution is calculated as a theoretical based on NA of wavelength 1550 nm

*3 Transmission rate, Focal Shift and Chromatic aberration are provisional values.
Standard wavelength is 1550nm.

*2 The working distance of PEIR 50x 2000HR is a provisional value.

*4 Compensating glass is needed for silicon correction. (Optional)



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